


**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Attorney Docket Number	1011-54375-01
Application Number	09/620,021
Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
<i>pme</i>		4,536,881	8.20.1985	Kasuya
		5,870,476	2.9.1999	Fischer
		5,872,793	2.16.1999	Attaway et al.
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<i>pmc</i>		6,829,740	12.7.2004	Rajski et al.

FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee
<i>pme</i>		Europe	EP 0372226	6.13.1990	Bardell
<i>pmr</i>		Europe	EP 0438322	7.24.1991	Murase
<i>pme</i>		Europe	EP 0481097	4.22.1992	Diebold et al.
<i>pme</i>		Japan	JP 4-236378	8.25.1992	Diebold et al.
<i>pme</i>		Japan	JP 9-130378	5.16.1997	Fischer English abstract
<i>pme</i>		Europe	EP 0887930	12.30.1998	Tarrab et al.
<i>pme</i>		Japan	JP 11-153655	6.8.1999	Park English abstract

EXAMINER SIGNATURE: <i>Phung Chung</i>	DATE CONSIDERED: <i>5/16/05</i>
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* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.


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qmc		Bassett et al., "Low-Cost Testing of High-Density Logic Components," <i>IEEE Design & Test of Computers</i> , pp. 15-28 (April 1990).
qmc		Fagot et al., "On Calculating Efficient LFSR Seeds for Built-In Self Test," <i>IEEE</i> , pp. 7-14 (1999).
qmc		Hellebrand et al., "Generation of Vector Patterns Through Reseeding of Multiple-Polynomial Linear Feedback Shift Registers," <i>IEEE International Test Conference</i> , pp. 120-129 (1992).
qmc		Wang, "BIST Using Pseudorandom Test Vectors and Signature Analysis," <i>IEEE Custom Integrated Circuits Conference</i> , pp. 1611-1618 (1998).

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